

### TOSHIBA Photocoupler GaAlAs Ired & Photo-Diode Array

# **TLP190B**

Telecommunication
Programmable Controllers
MOS Gate Driver
MOS FET Gate Driver

The TOSHIBA mini flat coupler TLP190B is a small outline coupler, suitable for surface mount assembly.

The TLP190B consists of a GaA $\ell$ As light emitting diode, optically coupled to a series connected photo diode array which is suitable for MOS FET gate drive.

Open voltage: 7.0V (min.)
Short current: 12.0µA (min.)
Isolation voltage: 2500Vrms (min.)
UL recognized: UL1577, file no. E67349

# Unit in mm 6 4 7.0 ± 0.4 1.4C1 TOSHIBA 11–4C1

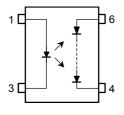
Weight: 0.09 g

## **Maximum Ratings (Ta = 25°C)**

Characteristic		Symbol	Rating	Unit
LED	Forward current	l <sub>F</sub>	50	mA
	Forward current derating (Ta ≥ 25°C)	ΔI <sub>F</sub> / °C	-0.5	mA / °C
	Pulse forward current (100µs pulse 100pps)	I <sub>FP</sub>	1	Α
	Reverse voltage	$V_{R}$	3	V
	Junction temperature	Tj	125	°C
	Forward current	I <sub>FD</sub>	50	μΑ
Detector	Reverse voltage	$V_{RD}$	10	V
	Junction temperature	Tj	125	°C
Storage temperature range		T <sub>stg</sub>	-55~125	°C
Operating temperature range		T <sub>opr</sub>	-40~85	°C
Lead solder	ing temperature (10 s)	T <sub>sol</sub>	260	°C
Isolation vol (AC, 1 min.,	tage R.H. ≤ 60%) (Note)	BV <sub>S</sub>	2500	Vrms

(Note) Device considered a two terminal device: Pins 1 and 3 shorted together and pins 4 and 6 shorted together.

# Pin Configuration (top view)



- 1. Anode
- 3. Cathode
- 4. Cathode
- 6. Anode

# **Recommended Operating Conditions**

Characteristic	Symbol	Min.	Тур.	Max.	Unit
Forward current	I <sub>F</sub>	_	20	25	mA
Operating temperature	T <sub>opr</sub>	-25	_	85	°C

# Individual Electrical Characteristics (Ta = 25°C)

Characteristic		Symbol	Test Condition	Min.	Тур.	Max.	Unit
	Forward voltage	V <sub>F</sub>	I <sub>F</sub> = 10 mA	1.2	1.4	1.7	V
LED	Reverse current	I <sub>R</sub>	V <sub>R</sub> = 3 V	_	_	10	μA
LLD	Capacitance	C <sub>T</sub>	V = 0, f = 1 MHz	-	30	60	pF
	Forward voltage	$V_{FD}$	I <sub>C</sub> = 10 μA	1	7		V
Detector	Reverse current	$I_{RD}$	V <sub>R</sub> = 10 V	_	1	_	nA
	Capacitance (anode to cathode)	C <sub>TD</sub>	V = 0, f = 1 MHz	ı	_	-	pF

# **Coupled Electrical Characteristics (Ta = 25°C)**

Characteristic	Symbol	Test Condition	MIn.	Тур.	Max.	Unit
Open voltage	V <sub>OC</sub>	I <sub>F</sub> = 10 mA	7	8	_	V
Short current	I <sub>SC</sub>	I <sub>F</sub> = 10 mA	12	20	_	μA

# **Isolation Characteristics (Ta = 25°C)**

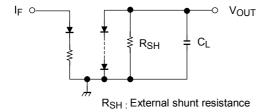
Characteristic	Symbol	Test Condition	Min.	Тур.	Max.	Unit
Capacitance input to output	CS	V <sub>S</sub> = 0, f = 1 MHz	_	0.8	_	pF
Isolation resistance	R <sub>S</sub>	V <sub>S</sub> = 500 V, R.H. ≤ 60%	5×10 <sup>10</sup>	10 <sup>14</sup>	_	Ω
Isolation voltage	BVS	AC, 1 minute	2500	_	_	Vrms
		AC, 1 second in oil	_	5000	_	VIIIIS
		DC, 1 minute in oil	_	5000	_	Vdc

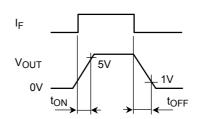
# **Switching Characteristics (Ta = 25°C)**

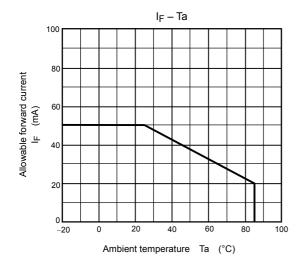
Characteristic	Symbol	Test Condition	Min.	Тур.	Max.	Unit
Turn-on time	t <sub>ON</sub>	$I_F$ = 20 mA, $R_{SH}$ = 510 kΩ	_	0.2	_	ms
Turn-off time	toff	$C_L = 1000pF$ (Fig. 1	)	1	_	ms

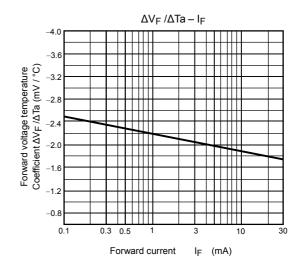
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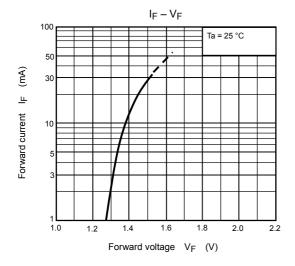
Fig. 1 Switching time test circuit

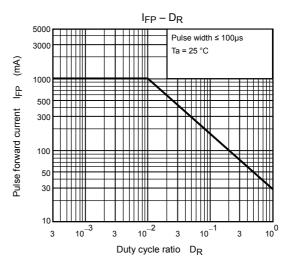


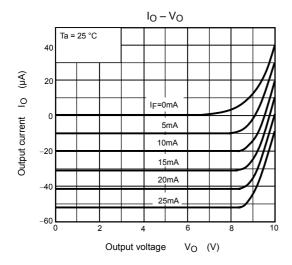


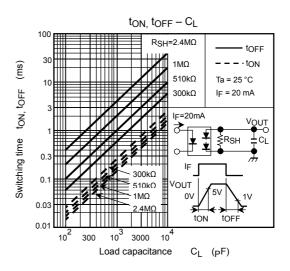


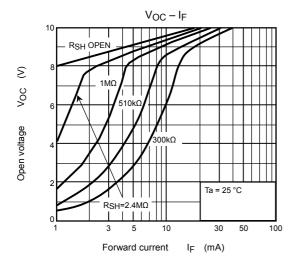


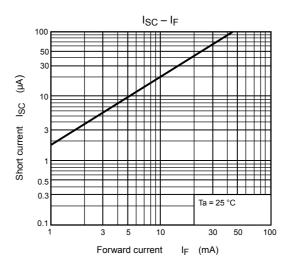


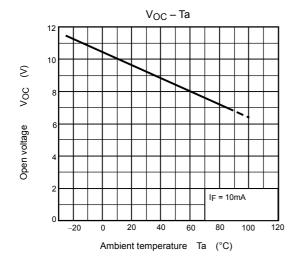


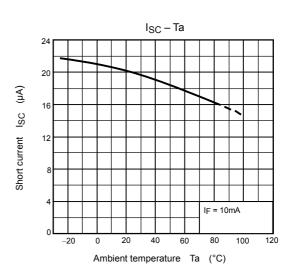












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